FAIRCHILD SEMICONDUCTOR®

May 2010

FDMA3023PZ

Dual P-Channel PowerTrench® MOSFET

-30 V, -2.9 A, 90 mΩ

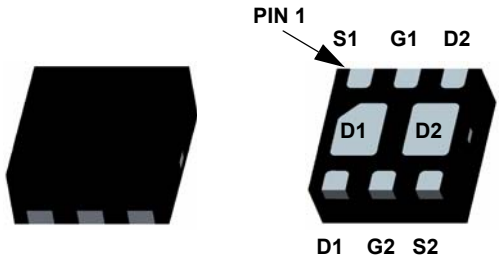
Features

- Max $r_{DS(on)}$ = 90 mΩ at V_{GS} = -4.5 V, I_D = -2.9 A
- Max $r_{DS(on)}$ = 130 mΩ at V_{GS} = -2.5 V, I_D = -2.6 A
- Max $r_{DS(on)}$ = 170 mΩ at V_{GS} = -1.8 V, I_D = -1.7 A
- Max $r_{DS(on)}$ = 240 mΩ at V_{GS} = -1.5 V, I_D = -1.0 A
- Low profile - 0.8 mm maximum - in the new package MicroFET 2x2 mm
- HBM ESD protection level > 2kV (Note 3)
- RoHS Compliant
- Free from halogenated compounds and antimony oxides

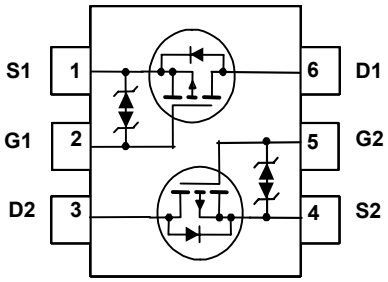
General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. When connec ted in the typical common source configuration, bi-directional current flow is possible.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.



MicroFET 2x2



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DS}	Drain to Source Voltage		-30	V
V_{GS}	Gate to Source Voltage		±8	V
I_D	Drain Current -Continuous	(Note 1a)	-2.9	A
	-Pulsed		-6	
P_D	Power Dissipation	(Note 1a)	1.4	W
	Power Dissipation	(Note 1b)	0.7	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1a)	86	°C/W
$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1b)	173	
$R_{\theta JA}$	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1c)	69	
$R_{\theta JA}$	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1d)	151	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
323	FDMA3023PZ	MicroFET 2X2	7 ”	8 mm	3000 units

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Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = -250 μA, V_{GS} = 0 V	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, referenced to 25 °C		-24		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = -24 V, V_{GS} = 0 V			-1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±8 V, V_{DS} = 0 V			±100	nA
On Characteristics						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = -250 μA	-0.4	-0.6	-1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μA, referenced to 25 °C		3		mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = -4.5 V, I_D = -2.9 A		71	90	mΩ
		V_{GS} = -2.5 V, I_D = -2.6 A		97	130	
		V_{GS} = -1.8 V, I_D = -1.7 A		122	170	
		V_{GS} = -1.5 V, I_D = -1.0 A		151	240	
		V_{GS} = -4.5 V, I_D = -2.9 A, T_J = 125 °C		110	140	
g_{FS}	Forward Transconductance	V_{DS} = -5 V, I_D = -2.9 A		10		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = -15 V, V_{GS} = 0 V, f = 1 MHz		400	530	pF
C_{oss}	Output Capacitance			55	70	pF
C_{rss}	Reverse Transfer Capacitance			45	65	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = -15 V, I_D = -1.0 A, V_{GS} = -4.5 V, R_{GEN} = 6 Ω		5	1 0	ns
t_r	Rise Time			4	1 0	ns
$t_{d(off)}$	Turn-Off Delay Time			62	100	ns
t_f	Fall Time			18	33	ns
$Q_{g(TOT)}$	Total Gate Charge	V_{DD} = -15 V, I_D = -2.9 A V_{GS} = -4.5 V		7.9	11	nC
Q_{gs}	Gate to Source Charge			0.9		nC
Q_{gd}	Gate to Drain “Miller” Charge			1.9		nC
Drain-Source Diode Characteristics						
I_S	Maximum Continuous Drain-Source Diode Forward Current				-1.1	A
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = -1.1 A (Note 2)		-0.8	-1.2	V
t_{rr}	Reverse Recovery Time	I_F = -2.9 A, di/dt = 100 A/μs		18	33	ns
Q_{rr}	Reverse Recovery Charge			6.6	13	nC

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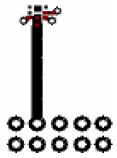
Notes:

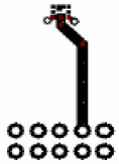
1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.
   (a) $R_{\theta JA}$ = 86 °C/W when mounted on a 1 in^2 pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For single operation.
   (b) $R_{\theta JA}$ = 173 °C/W when mounted on a minimum pad of 2 oz copper. For single operation.
   (c) $R_{\theta JA}$ = 69 °C/W when mounted on a 1 in^2 pad of 2 oz copper, 1.5 ” x 1.5 ” x 0.062 ” thick PCB. For dual operation.
   (d) $R_{\theta JA}$ = 151 °C/W when mounted on a minimum pad of 2 oz copper. For dual operation.

a)86 °C/W when mounted on a 1 in^2 pad of 2 oz copper.



b)173 °C/W when mounted on a minimum pad of 2 oz copper.

c)69 °C/W when mounted on a 1 in^2 pad of 2 oz copper.



d)151 °C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test : Pulse Width < 300 us, Duty Cycle < 2.0%
3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

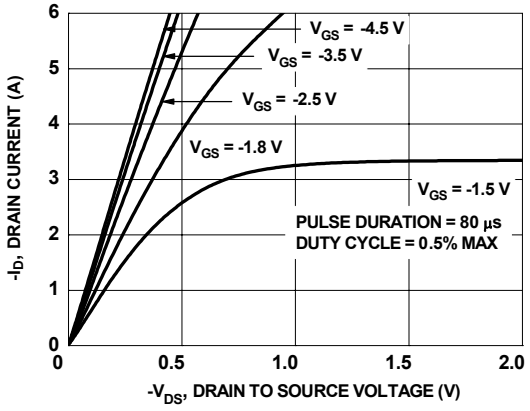


Figure 1. On Region Characteristics

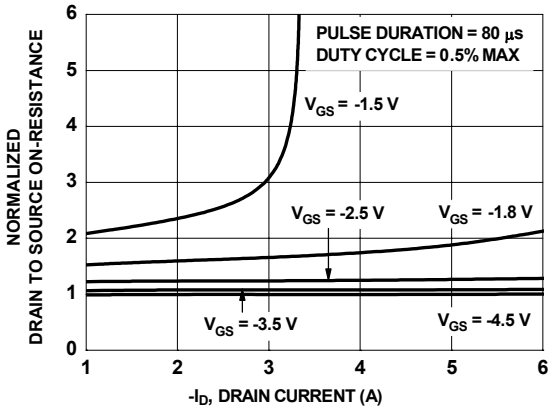


Figure 2 Normalized On-Resistance vs Drain Current and Gate Voltage

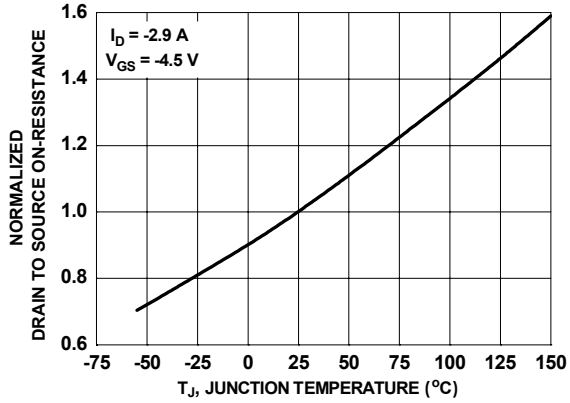


Figure 3. Normalized On Resistance vs Junction Temperature

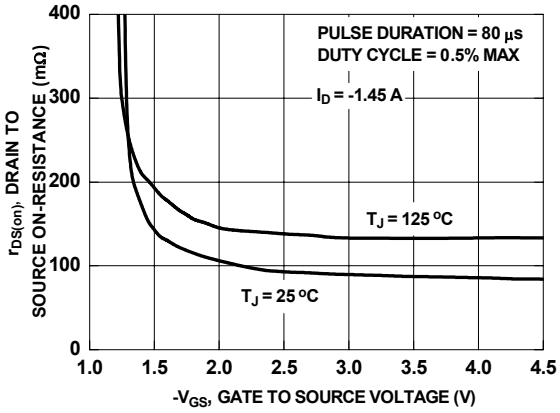


Figure 4. On-Resistance vs Gate to Source Voltage

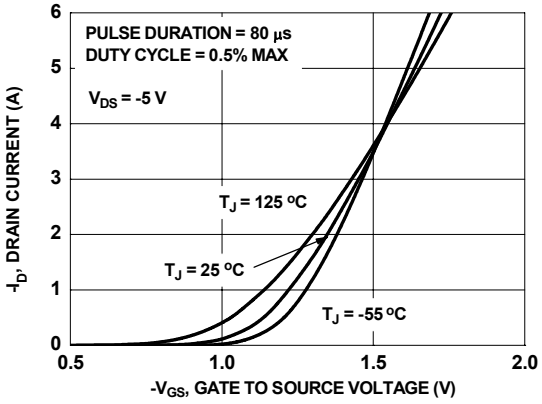


Figure 5. Transfer Characteristics

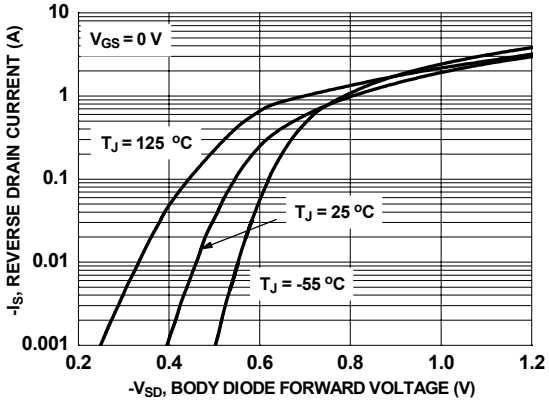


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

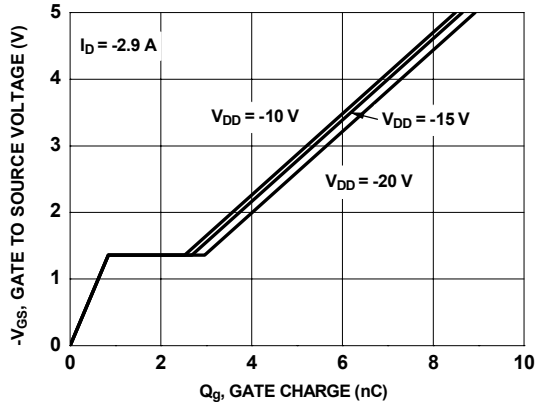


Figure 7. Gate Charge Characteristics

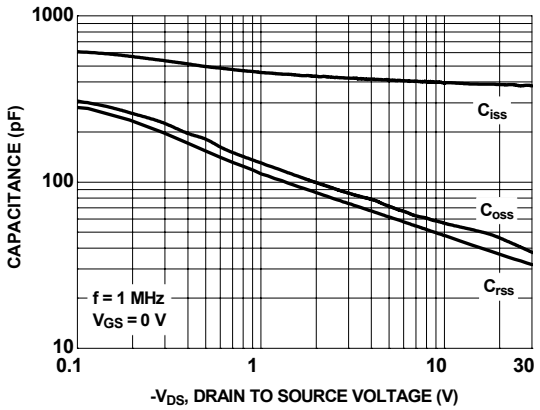


Figure 8. Capacitance vs Drain to Source Voltage

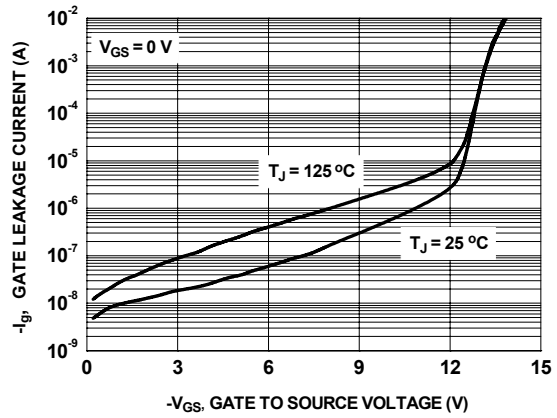


Figure 9. Gate Leakage vs Gate to Source Voltage

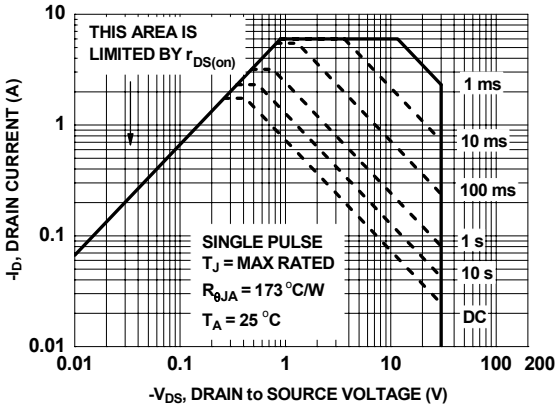


Figure 10. Forward Bias Safe Operating Area

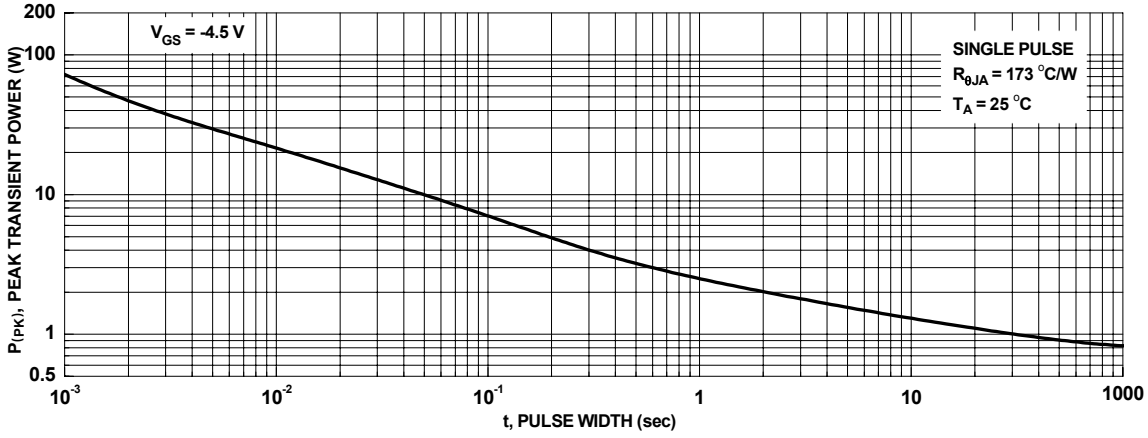


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

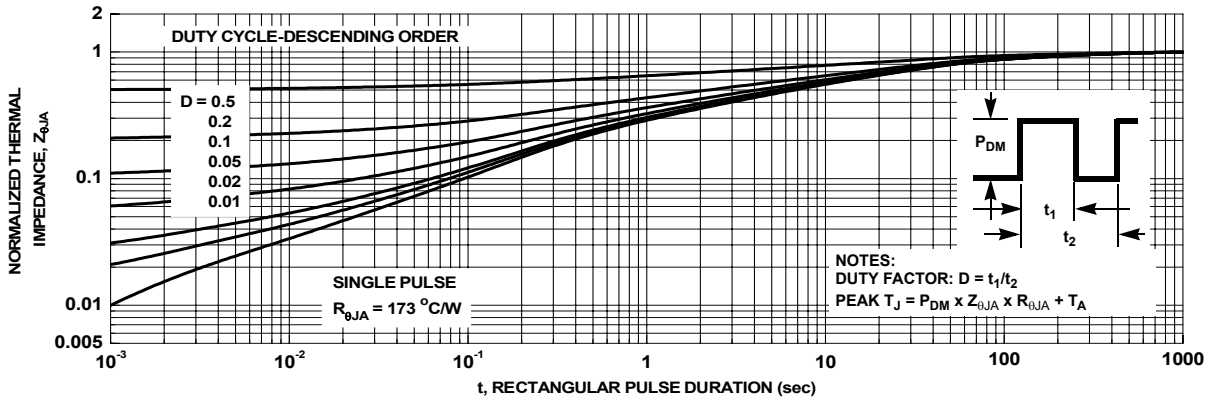
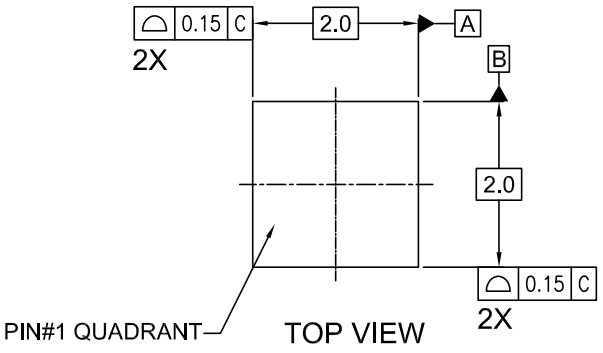
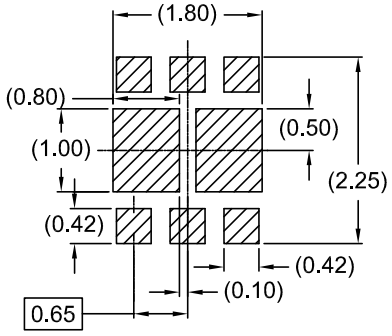


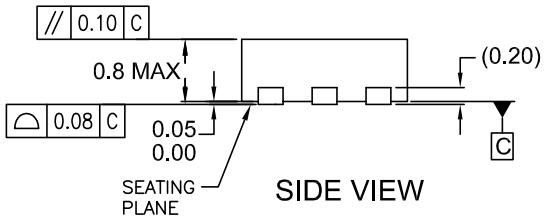
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

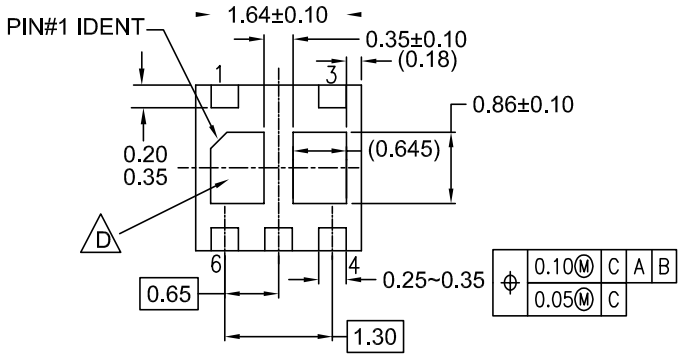
Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN





BOTTOM VIEW

NOTES:

A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC EXCEPT AS NOTED.

B. DIMENSIONS ARE IN MILLIMETERS.

C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

D. NON-JEDEC DUAL DAP

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